

<b>Notice of References Cited</b>	Application/Control No. 10/780,244		Applicant(s)/Patent Under Reexamination HEO ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,940,111 B2	09-2005	Bruchhaus et al.	257/295
*	B	US-2005/0133876 A1	06-2005	Bu et al.	257/408
*	C	US-2005/0111248 A1	05-2005	Pan, Pai-Hung	365/049
*	D	US-6,887,720 B2	05-2005	Joo, Suk-Ho	438/3
*	E	US-6,876,021 B2	04-2005	Martin et al.	257/295
*	F	US-6,849,544 B2	02-2005	Weimer et al.	438/656
*	G	US-6,844,252 B2	01-2005	Pan, Pai-Hung	438/595
*	H	US-6,815,227 B2	11-2004	An, Hyeong-Geun	438/3
*	I	US-2004/0203222 A1	10-2004	Pyi, Seung Ho	438/592
*	J	US-6,800,890 B1	10-2004	Wohlfahrt et al.	257/295
*	K	US-2004/0104754 A1	06-2004	Bruchhaus et al.	327/294
*	L	US-6,717,197 B2	04-2004	An, Hyeong-Geun	257/295
*	M	US-6,717,196 B2	04-2004	Joo, Suk-Ho	257/295

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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#### NON-PATENT DOCUMENTS

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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,713,342 B2	03-2004	Celii et al.	438/239
*	B	US-6,514,842 B1	02-2003	Prall et al.	438/593
*	C	US-6,514,841 B2	02-2003	Kim et al.	438/592
*	D	US-2002/0048920 A1	04-2002	PAN, PAI-HUNG	438/595
*	E	US-2002/0063283 A1	05-2002	Pan et al.	257/344
*	F	US-6,380,008 B2	04-2002	Kwok et al.	438/158
*	G	US-2002/0048920 A1	04-2002	PAN, PAI-HUNG	438/595
*	H	US-6,333,250 B1	12-2001	Kim, Hyeon Soo	438/595
*	I	US-6,277,722 B1	08-2001	Lee et al.	438/592
*	J	US-6,308,309 B1	10-2001	Gan et al.	716/8
*	K	US-6,288,419 B1	09-2001	Prall et al.	257/213
*	L	US-6,198,144 B1	03-2001	Pan et al.	257/412
*	M	US-6,075,274 A	06-2000	Wu et al.	257/413

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,998,290 A	12-1999	Wu et al.	438/595
*	B	US-5,925,918 A	07-1999	Wu et al.	257/413
*	C	US-5,796,166	08-1998	Agnello et al.	257/751
*	D	US-5,776,823	07-1998	Agnello et al.	438/592
*	E	US-5,739,066	04-1998	Pan, Pai-Hung	438/595
*	F	US-5,576,576	11-1996	Hawley et al.	257/530
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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